M esoscopic oscillations of the conductance of disordered m etallic samples as a function of temperature

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We show theoretically and experimentally that the conductance of small disordered samples exhibits random oscillations as a function of temperature. The amplitude of the oscillations decays as a power law of temperature, and their characteristic period is of the order of the temperature itself.

At low temperatures the conductance of small disordered metallic samples uctuates from sample to sample. There are two contributions to the amplitude of the uctuations. The rst is associated with a classical elect: the D rude conductivity depends on the concentration of impurities, which uctuates in space. The second electron quantum interference. As a consequence of the latter, the conductance of an individual sample exhibits random oscillations as a function of external magnetic eld and chemical potential. The goal of this communication is to point out that the conductance G (T) of an individual mesoscopic metallic sample also oscillates as a function of temperature.

The well known picture of mesoscopic uctuations of the conductance between samples, and of oscillations of the conductance of individual samples as a function of magnetic eld and chemical potential, is as follows. When the sample conductance G e²=h is large and at zero temperature T = 0, the variance of the interference contribution is universal,

$$h(G)^2 i = \frac{e^4}{h^2};$$
 (1)

and independent of sam ple size [1, 2]. Here G=G hG i, the brackets hi denote averaging over a random scattering potential, and is a coe cient of order unity which depends on the dimensionality of the sam ple and its geometry. One can get Eq. 1 by calculating the diagram shown in Fig.1. (We use a standard diagram technique for averaging over random scattering potential [4].) The conductance of an individual sample, G(H), exhibits random sample specic oscillations as a function of external magnetic eld H [1, 3]. We will consider for example the sample geometry shown in the inset of Fig.2, and assume that the sample size L is much larger than the elastic mean free path, L l. If the magnetic length L_H L and at T=0, the amplitude of the oscillations is given by Eq. 1, while their characteristic period is H $_0=L^2$, where $_0=h=c$ is the ux quantum. This statement follows from the magnetic eld dependence of the correlation function,

h(G(H + H)G(H))i
$$\frac{e^4}{h^2}$$
 (H): (2)

At H H the correlation function has the asymptotic behavior (H) L $_{\rm H}$ =L and approaches zero. This can be shown by calculating the diagram in Fig.1, assuming that the inner solid lines correspond to electron G reen functions at magnetic eld H while the outer solid lines correspond to G reen functions at H + H . The oscillations of the conductance as a function of H in the regime where $L_{\rm T}$ L $_{\rm H}$ L were discussed in [5]. Here $L_{\rm T}$ = D =T, where D is the di usion coe cient of the m etal. For example in the three-dimensional (3d) case the amplitude of the oscillations decays as $L_{\rm H}^{-1}$ while their period is of order H . Thus in this regime the typical period of the oscillations decreases while the derivative dG =dH diverges as H ! 0. To get these results one has to assume that the electron di usion coe cient in the leads is the same as in the sample.

The oscillations mentioned above are of a single-particle interference nature. Contributions to G from electron wave functions with dierent energies, generally speaking, have dierent signs. As the temperature T increases, cancellation of contributions at dierent energies becomes more elective, leading to a decay of the amplitude of the mesoscopic oscillations.

In this article we show that the tem perature dependence of the conductance G (T) of an individual sample is actually a non-monotonic function of the tem perature T and exhibits random sample specic oscillations. The characteristic period of the oscillations T is of the order of the tem perature itself, that is,

$$T T:$$
 (3)

To prove the existence of the oscillations we calculate the correlation function

$$h G (T_1) G (T_2) i = \frac{2e^2D}{h} = \frac{2}{L} = \frac{1}{L} = \frac{4 d Z_1}{0} = \frac{1}{L} = \frac{4 d Z_1}{0} = \frac{1}{L} = \frac{2}{L} = \frac{1}{L} + \frac{1}{L} = \frac{1}{L$$

where is the electron phase breaking time, and

$$B(z) = \frac{z}{\sinh z};$$
 (5)

It follows from Eq. 4 that in the $\lim_{t \to 0} T^0$ D = L^2

$$h G (T))^{2} i = \frac{e^{4}}{h^{2}} \frac{\int_{T^{1-2}L}^{1-2}}{\int_{TL^{2}}^{1-2} \ln(_{0}T) \text{ for } d = 3}$$
(6)

and

$$h G (T^{0}) G (T) i = \begin{pmatrix} e^{4} & \frac{D^{1-2}}{T^{1-2}L} (1 & 0.4 \frac{T^{0}}{T})^{2}) & \text{for } d = 3 \\ \frac{D^{1-2}}{T^{1-2}L} \ln (0.T) (1 & 0.8 \frac{T}{T^{0}})^{2}) & \text{for } d = 2 \end{pmatrix}$$
(7)

Here $_0$ = m inf $_i$ D =L 2 g, and $_1$ is a coe cient of order unity which depends on the sample geometry. To get Eq. 6 one can calculate the diagram shown in Fig. 1 where the electron G reen functions in the inner and the outer loops are taken at the same temperature T. To get Eq. 7 one has to take the G reen functions in the inner loop at T 0 and in the outer loop at T.

The existence of the oscillations of the conductance G (T) as a function of T, and the fact that G (T) changes sign, follow from the facts that the powers of tem perature in the denominators of T, and T are the same, and that T is independent of T for T T (For example a typical monotonic form T T cannot satisfy both T T and T even if the coecient T has a random sample-species sign.) A typical realization of the tem perature dependence of the conductance has the form

$$G(T) = h(G(T))^2 i^{1-2} F(T);$$
 (8)

where the function F (T) random ly oscillates about zero with a characteristic period of order T.

In the opposite lim it T $D=L^2$, (ie. L_T L), the tem perature dependence of G (T) depends on the properties of the leads. In the lim it $D_L=D$! 1, where D_L is the di usion one cient in the leads, the function G (T) vanishes monotonically as T! 0. However, if D_L D the T-dependence of G (T) has similar features to its H-dependence in the lim it L_T L_H L [5]. That is, G (T) exhibits random oscillations whose amplitude decays as T! 0. The period of the oscillations for T $D=L^2$ is again of order T T. The latter statement follows from the T dependence of the following correlation functions at T 0 T,

$$h(\frac{d G (T)}{dT})^2 i = \frac{1}{T^{3 d=2}}$$
 (9)

and

$$h \frac{d G (T^{0})}{dT^{0}} \frac{d G (T)}{dT} i \frac{T^{0}}{T^{4 d=2}}$$
(10)

which can be obtained by calculation of diagrams in Fig.1 as in [5]. According to Eqs_p $\frac{9}{D}$ and 10 the value of the derivative dG=dT diverges as T ! 0. This is correct as long as L L_T, where L = $\frac{9}{D}$ is the electron phase breaking length. The latter inequality holds if the value of L is determined by electron-electron or electron-phonon scattering [6]. The qualitative temperature dependence of G (T) in this case is shown in Fig.2.

At very low temperatures the value of L is determined by the paramagnetic impurities in the sample and is temperature independent as long as the K ondo e ect and exchange between paramagnetic spins are not signicant. In the case L L_T the amplitude of the oscillations of dG =dT decays as T ! 0. Thus the typical amplitude of the oscillations of the derivative dG =dT has a maximum when L_T L; and the total number of oscillations is of order ln (T $_S$), where $_S$ is the spin relaxation time.

The oscillations as a function of tem perature discussed above should be present in any therm odynam ic or transport property of m esoscopic m etallic sam ples.

To test the theory we study som e m easurem ents of conductance oscillations in a silicon M O SFET as a joint function of gate voltage V_g and tem perature T . The chosen device has a square channel of length and w idth L = 1 m . The oxide thickness is 25 nm , giving a gate capacitance per unit area of 8:6 = 10^{11} e cm 2 V 1 . The source and drain contacts are n++ doped silicon. The average conductance, m easured by passing an ac current of 5 nA , varies approximately linearly from $19e^2$ =h at $V_g = 4$ V to $26e^2$ =h at $V_g = 5$ V . For practical purposes, the device behaves as a square of disordered 2D electron gas with m obility = 2000 cm 2 V 1 s 1 and m omentum scattering length 1 = 30 nm , having

3D m etallic contacts. M easurem ents of conductance oscillations as a function of m agnetic eld [8] indicate that the channel is phase coherent at the base tem perature of 35 m K achieved on the dilution refrigerator.

The data presented in Fig. 3 are derived from sweeps of V_g at a series of tem peratures between 35 mK and 12 K. (Note that a constant perpendicular magnetic eld of 0.1 T was present in all measurements.) A smooth monotonic background variation of the mean conductance hG i with V_g and T has been subtracted from the raw data, so that the quantity plotted in the gure is the deviation from this background, G = G hG i. The sweeps show reproducible oscillations which decay and broaden as T increases, as illustrated in Fig. 3a. The variance h(G)² i and correlation gate voltage V_g are plotted against T in Fig. 3b. Fig. 3c is a greyscale plot of G vs V_g and T, where peaks are light and dips are dark. The appearance of this plot, where individual extrem a evolve steadily with T, gives us con dence that the data at dierent temperatures can be compared reliably.

Fig. 3d shows the variation of G with $\log T$ at a set of evenly spaced values of V_g . The curves here are smooth splines passing through the eight temperature points at each V_g and extrapolating towards G=0 at T=1.2 K. For clarity, the actual data points are marked as solid circles on only one of the curves. It is apparent that G oscillates random by with T on a logarithm is scale, in qualitative accordance with our predictions. O ver the factor-of-30 temperature range here, at each gate voltage typically one or two oscillations are resolved. Selected curves have been drawn in bold to illustrate the variety of the oscillatory behavior.

It is quite surprising that these oscillations of the conductance as a function of temperature have never been pointed out in either the theoretical or the experim ental literature.

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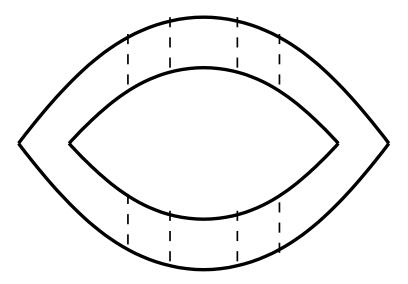
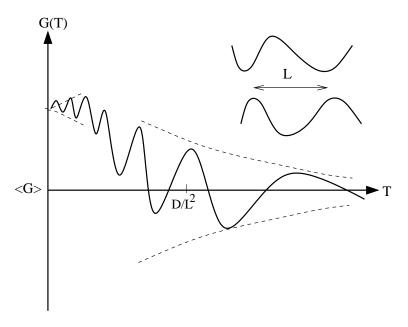


FIG.1: D iagram describing the correlation function hG (H; T)G (H $^{\circ}$; T $^{\circ}$)i. Solid lines correspond to electron G reen functions, and thin dashed lines correspond to the correlation function of the random scattering potential.



 $\textit{F IG . 2:} \ \, \textit{T ypical tem perature dependence of the conductance G (T). Insert: schem atic diagram of the sam ple. } \, \\$

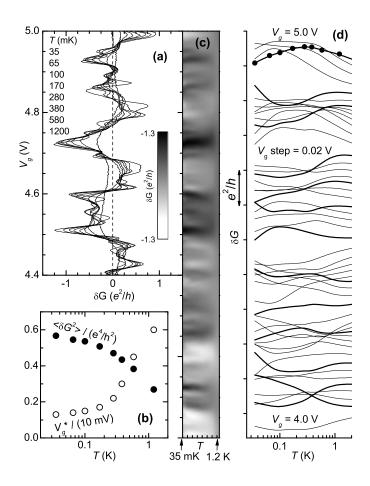


FIG. 3: M easurements of the conductance oscillations G in a silicon MOSFET. (a) G ate voltage (V_g) sweeps at a series of temperatures (T) listed at the top left. (b) Variance h(G) i and correlation gate voltage V_g (the half-width of the autocorrelation function) of the oscillations as a function of temperature, obtained by averaging over V_g . (c) G reyscale plot of G vs T and V_g . (d) Temperature dependence of G at $V_g = 4.0;4.02; ::::5.0$ V, with consecutive sweeps o set vertically by $0.2e^2 = h$.